

INFORMATION DISCLOSURE CITATION <small>(use several sheets if necessary)</small>		Docket Number (Optional) UC01-161-2	Application Number 10/039,290
		Applicant(s) ALI SHAKOURI ET AL.	
		Filing Date JANUARY 4, 2002	Group Art Unit 2633
*EXAMINER INITIALS <i>CS</i>	OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>		
<i>CS</i>	Bartoli, J. et al.; "SUBSURFACE MICROSCOPY OF BIASED METAL-OXIDE-SEMICONDUCTOR FIELD EFFECT TRANSISTOR STRUCTURES: PHOTOTHERMAL AND ELECTROREFLECTANCE IMAGES," Sensors and Actuators, A71, pp. 40 thru 45, (1998).		
<i>CS</i>	Claeys, W. et al.; "THERMOREFLECTANCE OPTICAL TEST PROBE FOR THE MEASUREMENT OF CURRENT INDUCED TEMPERATURE CHANGES IN MICROELECTRIC COMPONENTS," Quality and Reliability Engineering International, Vol. 9, pp. 303-308, (1993).		
<i>CS</i>	Csendes, A. et al.; "THERMAL MAPPING WITH LIQUID CRYSTAL METHOD," Microelectronic Engineering, Col. 31, pp. 281-290, (1996).		
<i>CS</i>	Cutolo, Antonello; "SELECTED CONTACTLESS OPTOELECTRONIC MEASUREMENTS FOR ELECTRONIC APPLICATIONS (Invited)," Review of Scientific Instruments, Vol. 69, No. 2; pp. 337-360, February, 1998.		
<i>CS</i>	Garfinkel, J. et al.; "PIEZOREFLECTIVITY OF THE NOBLE METALS," Physical Review, Vol. 115, No. 1; pp. 695-706, August, 1966.		
<i>CS</i>	Goodson, K.E. and Ju, Y.S.; "SHORT-TIME-SCALE THERMAL MAPPING OF MICRODEVICES USING A SCANNING THEROREFLECTANCE TECHNIQUE," Transactions of the ASME, Vol. 120, pp. 306-313, May, 1998.		
<i>CS</i>	Grauby, S. et al.; "HIGH RESOLUTION PHOTOTHERMAL IMAGING OF HIGH FREQUENCY PHENOMENA USING A VISIBLE CHARGE COUPLED DEVICE CAMERA ASSOCIATED WITH A MULTICHANNEL LOCK-IN SCHEME," Review of Scientific Instruments, Vol. 70, No. 9, pp. 3603 thru 3608, September, 1999.		
<i>CS</i>	Herman, I. P.; "REAL-TIME OPTICAL THERMOMETRY DURING SEMICONDUCTOR PROCESSING," IEEE Journal of Selected Topics in Quantum Electronics, Vol. 1, No. 4, pp. 1047-1053, December, 1995.		
<i>CS</i>	Ju, S., Kading, O. et al.; "SHORT-TIMESCALE THERMAL MAPPING OF SEMICONDUCTOR DEVICES," IEEE Electron Device Letters, Vol. 18, No. 5, pp. 169-171, May, 1997.		
<i>CS</i>	Kolzer, J. et al.; "THERMAL IMAGING AND MEASUREMENT OF TECHNIQUES FOR ELECTRONIC MATERIALS AND DEVICES," Microelectronic Engineering, Vol. 31, pp. 251-270, (1996).		
<i>CS</i>	Kondo, Seiichi et al.; "HIGH RESOLUTION TEMPERATURE MEASUREMENT OF VOID DYNAMICS INDUCED BY ELECTROMIGRATION IN ALUMINUM METALLIZATION," Applied Physics Letters, Vol. 67, No. 11, pp. 1606-1608, September, 1995.		
<i>CS</i>	Langer, G. et al.; "THERMAL CONDUCTIVITY OF THIN METALLIC FILMS MEASURED BY PHOTOTHERMAL PROFILE ANALYSIS," Review of Scientific Instruments, Vol. 68, No. 3, pp. 1510-1513, March, 1997.		
EXAMINER <i>[Signature]</i>	DATE CONSIDERED 9/1/05		

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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*EXAMINER INITIAL <i>CS</i>	OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>		
	<p>Lee, A.S. and Norris, P.M.; "A NEW OPTICAL METHOD FOR MEASURING SURFACE TEMPERATURE AT LARGE INCIDENT PROBE ANGLES," Review of Scientific Instruments, Vol. 68, No. 2, pp. 1307-1311, February, 1997.</p>		
<i>CS</i>	<p>Litvinenko, S. et al.; "APPLICATION OF DYNAMICAL OPTICAL REFLECTION THERMOGRAPHY(DORT) FOR DETECTING OF DARK CURRENT INHOMOGENEITY IN SEMICONDUCTOR DEVICES," Applied Surface Science, Vol. 137, pp. 45-49, (1999)</p>		
<i>CS</i>	<p>Mansanares, A. et al.; "TEMPERATURE MEASUREMENTS OF TELECOMMUNICATION LASERS ON A MICROMETRE SCALE," Electronics Letters, Vol. 29, No. 23, pp. 2045-2047, (1993).</p>		
<i>CS</i>	<p>Phan, T.; "THERMOREFLECTANCE MEASUREMENTS OF TRANSIENT TEMPERATURE UPON INTEGRATED CIRCUITS: APPLICATION TO THERMAL CONDUCTIVITY IDENTIFICATION," Microelectronics Journal, Vol. 29, pp. 181-190, (1998).</p>		
<i>CS</i>	<p>Quintard, V. et al.; "TEMPERATURE MEASUREMENT OF METAL LINES UNDER CURRENT STRESS BY HIGH-RESOLUTION LASER PROBING," IEEE Transactions on Instrumentation and Measurement, Vol. 48, No. 1, pp. 69-74, February, 1999.</p>		
<i>CS</i>	<p>Willenborg, A. et al.; "DETECTION OF THERMAL WAVES THROUGH OPTICAL REFLECTANCE," Applied Physics Letters, Vol. 46, No. 11, pp. 1013-1015, June, 1985.</p>		
<i>CS</i>	<p>Spirig, T.; "THE LOCK IN CCD-TWO DIMENSIONAL SYNCHRONOUS DETECTION OF LIGHT," IEEE Journal of Quantum Electronics, Vol. 31, No. 9, pp. 1705-1708, September, 1995.</p>		
<i>CS</i>	<p>Vertikov, M. et al.; "TIME RESOLVED PUMP-PROBE EXPERIMENTS WITH SUBWAVELENGTH LATERAL RESOLUTION," Applied Physics Letters, Vol. 69, No. 21, pp. 2465-2467, October, 1996.</p>		
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CS Elad, Michael and Feuer, Arie; "RESTORATION OF A SINGLE SUPERRESOLUTION IMAGE FROM SEVERAL BLURRED, NOISY, AND UNDERSAMPLED MEASURED IMAGES," IEEE Transactions on Image Processing, Vol. 6, No. 12, pp. 1646-1658, December, 1997.

CS Hardie, Russell C., Barnard, Kenneth J., and Armstrong, Ernest E.; "JOINT MAP REGISTRATION AND HIGH-RESOLUTION IMAGE ESTIMATION USING A SEQUENCE OF UNDERSAMPLED IMAGES," IEEE Transactions on Image Processing, Vol. 6, No. 12, pp. 1621-1633, December, 1997.

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CS Irani, Michal and Peleg, Shmuel; "SUPER RESOLUTION FROM IMAGE SEQUENCES," Proceedings, 10th International Conference on Pattern Recognition, Vol. 2, pp. 115-120, June, 1990.

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